

Grain Analyzer Sector Agenda

August 16-17, 2017

INTRODUCTION

The charge of the NTETC Grain Analyzer Sector is important in providing appropriate type evaluation criteria based on specifications, tolerances and technical requirements of *NIST Handbook 44* Sections 1.10. General Code, 5.56. Grain Moisture Meters and 5.57. Near-Infrared Grain Analyzers. The sector's recommendations are presented to the National Type Evaluation Program (NTEP) Committee each January for approval and inclusion in *NCWM Publication 14 Technical Policy, Checklists, and Test Procedures* for national type evaluation.

The sector is also called upon occasionally for technical expertise in addressing difficult *NIST Handbook 44* issues on the agenda of National Conference on Weights and Measures (NCWM) Specifications and Tolerances (S&T) Committee. Sector membership includes industry, NTEP laboratory representatives, technical advisors, and the NTEP Administrator. Meetings are held annually, or as needed and are open to all NCWM members and other registered parties.

Suggested revisions are shown in **bold face print** by ~~striking out~~ information to be deleted and underlining information to be added. Requirements that are proposed to be nonretroactive are printed in *bold faced italics*.

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Table B
Glossary of Acronyms and Terms

Acronym	Term	Acronym	Term
BIML	International Bureau of Legal Metrology	NTETC	National Type Evaluation Technical Committee
CD	Committee Draft	OCP	Ongoing Calibration Program

CIML	International Committee of Legal Metrology	OIML	International Organization of Legal Metrology
CIPM	International Committee of Weights and Measures	OWM	Office of Weights and Measures
D	Document	R	Recommendation
EMRP	European Metrology Research Program	S&T	Specifications and Tolerances
FGIS	Federal Grain Inspection Service	SC	Subcommittee
GA	Grain Analyzer	SD	Secure Digital
GIPSA	Grain Inspection, Packers and Stockyards Administration	TC	Technical Committee
GMM	Grain Moisture Meter	TW	Test Weight
MRA	Mutual Recognition Agreement	UGMA	Unified Grain Moisture Algorithm
NCWM	National Conference on Weights and Measures	USB	Universal Serial Bus
NIR	Near Infrared Grain Analyzer	USDA	United States Department of Agriculture
NIST	National Institute of Standards and Technology	USNWG	United States National Working Group
NTEP	National Type Evaluation Program		

Details of All Items
(In order by Reference Key)

1. Selecting a new NTETC GA Chairperson

The Grain Analyzer (GA) Sector nominated Karl Cunningham to serve as the NTETC GA Chairperson and he has served in this position since the 2015 Grain Analyzer Sector Meeting. Karl requested that the selection of a new NTETC chairperson be added to the 2017 GA Sector agenda. Karl has been instrumental in assistance with grain sample distributions for proficiency test and has agreed to continue to assist in this capacity. In accordance with the NTEP Administrative policies there is no fixed term for the NTETC GA Chair position, the Sector Chair must be a member of NCWM, and the Sector Chair is appointed by the NTEP committee Chair. Sector members are asked to consider nominations for a New Committee Chair for the 2018 NTETC GA Sector.

2. Report on the 2016 NCWM Interim and Annual Meetings

The 2017 NCWM Interim Meeting was held January 8-11 in San Antonio, Texas. The 2017 NCWM Annual Meeting was held July 16-20 in Pittsburgh, Pennsylvania. At these meetings there were no Grain Analyzer Sector recommended changes to NCWM Publication 14 or NIST Handbook (HB) 44. The Grain Analyzer Sector originally submitted an item on the S&T agenda, which was subsequently reassigned to NIST, OWM for development. See Grain Analyzer Agenda Item 4 concerning the definition of remote configuration for an update of activities on this item.

Mr. Jim Truex, NTEP Administrator, will provide an update on the Interim and Annual Meetings.

3. Report on NTEP Evaluations and Ongoing Calibration Program (OCP) (Phase II) Testing

Mr. Jason Jordan, Grain Inspection, Packers and Stockyards Administration (GIPSA), the NTEP Participating Laboratory for grain analyzers, provided a list of grain analyzers that are enrolled in the Phase II for the 2016 harvest. There are 8 grain analyzer models enrolled for the 2016 harvest.

The 8 models:

1. Dickey-john Corp. – GAC2500-UGMA
2. Dickey-john Corp. – GAC2000, GAC2100, GAC2100a and GAC2100b
3. Perten Instruments Inc. - AM5200 and AM5200-A (UGMA)
4. Perten Instruments Inc. – IM9500 and IM9500 HLW/TW
5. Foss North America – Infratec 1241
6. Foss North America – Infratec Nova
7. The Steinlite Corp. – SL95
8. MTC Moisture Analyzers – MTC 999 ES

Mr. Jordan will provide the sector with an update on the NTEP Phase I evaluations and report on the collection and analysis of the OCP (Phase II) data from the 2016 crop year.

4. Review of OCP (Phase II) Performance Data For Moisture and Test Weight per Bushel

At the Sector’s August 2005 meeting it was agreed that comparative OCP data identifying the Official Meter and listing the average bias for each NTEP meter type should be available for annual review by the sector. Accordingly, Mr. Jordan, GIPSA, the NTEP Participating Laboratory for grain analyzers provided data for inclusion in the 2017 Grain Analyzer Sector Report showing the performance of NTEP meters compared to the air oven. This data is based on the last three crop years (2014–2016) using calibrations updated for use during the 2016 harvest season.

The 2014-2016 Grain Moisture Meter (GMM) Phase II comparison graphs are available for view or can be downloaded for printing at the following web address:

<https://www.ncwm.net/ntep/sectors/grain-analyzer/meeting-documents>

At the Sector’s August 2012 meeting, it was agreed that TW comparison and correlation charts should be prepared for the 3 grains which are most likely to be subject to discounts on the basis of TW: Corn and two wheat classes and limited to Air Oven reference values less than 20% moisture. The wheat classes selected were: Hard Red Winter and Soft Red Winter. Accordingly, Mr. Jordan, GIPSA, the NTEP Participating Laboratory for Grain analyzers prepared data showing the performance of NTEP meters compared to the GIPSA reference Quart Kettle Test Weight Apparatus. Mr. Jordan provided this information for the Grain Analyzer Sector 2017 report. This data is based on the last three crop years (2014 – 2016) using calibrations updated for use during the 2016 harvest season.

The 2014-2016 TW comparison and correlation charts and TW Phase II data are available for view or can be downloaded for printing at the following web address:

<https://www.ncwm.net/ntep/sectors/grain-analyzer/meeting-documents>

5. Modify the Definition of Remote Configuration Capability Appearing in Appendix D of NIST Handbook 44 to Recognize the Expanded Scope of “Remote Configuration Capability” (S&T Developing item 3600-5)

Source:

Originally proposed by the Grain Analyzer Sector but because NIST, OWM recognized that this item would affect other device types it was reassigned to NIST, OWM for further development.

Purpose:

Table S.2.5. *Categories of Device and Methods of Sealing* that appears in §5.56.(a) of *NIST Handbook 44* lists acceptable methods of sealing for various categories of GMMs. When the sector first recommended adding the table to *NIST Handbook 44* at their September 1996 meeting, the concept of making a change to a GMM from a remote site involved information “...sent by to the device by modem (or computer).” In 2011 this concept has expanded to include the ability of the measuring device to accept new or revised sealable parameters from a memory chip (e.g., an SD Memory Card that may or may not itself be necessary to the operation of the device), external computer, network, or other device plugged into a mating port (e.g., Universal Serial Bus (USB) port) on the measuring device or connected wirelessly to the measuring device. The changes proposed in Item Under Consideration expand the scope of “remote configuration capability” to cover instances where the “other device” may be necessary to the operation of the weighing or measuring device or which may be considered a permanent part of that device.

Item Under Consideration:

Modify the General Code by adding the following paragraph to address security for systems adjusted using removable media:

G-S.8.2. Devices and Systems Adjusted Using Removable Digital Storage Device. - For devices and systems in which the configuration or calibration parameters can be changed by use of a removable digital storage device, such as a secure digital (SD) card, USB flash drive, etc., security shall be provided for those parameters using an event logger in the device. The event logger shall include an event counter (000 to 999), the parameter ID, the date and time of the change, and the new value of the parameter. A printed copy of the information must be available on demand through the device or through another on-site device. In addition to providing a printed copy of the information, the information may be made available electronically. The event logger shall have a capacity to retain records equal to 10 times the number of sealable parameters in the device, but not more than 1000 records are required. (Note: Does not require 1000 changes to be stored for each parameter.)

(Added 20XX)

and exempt current sealing requirements from applying to devices and systems adjusted using a removable digital storage device by proposing changes to the sealing requirements in the following HB 44 code sections: 2.20., 2.21., 2.22., 2.24., 3.30., 3.31., 3.32., 3.33., 3.34., 3.35., 3.36., 3.37., 3.38., 3.39, 3.40., 5.55., 5.56.(a), and 5.58. This exemption is needed because the General Code paragraph being proposed will address the sealing of all device types and systems that can be adjusted using a removable digital storage device.

The following is an example of proposed changes to the Grain Moisture Meter Code, which are intended to provide the exemption noted for NIST HB 44, Section 5.56(a):

S.2.5. Provision for Sealing.

S.2.5.1. Devices and Systems Adjusted Using a Removable Digital Storage Device. - For those devices and systems in which calibration and configuration parameters, as defined in Appendix D, can be changed by use of removable digital storage device, security shall be provided for those parameters as specified in G-S.8.2 .

S.2.5.2. All Other Devices.- Except on devices specified in S.2.5.1 and S.2.5.3. Provision shall be made for applying a security seal in a manner that requires the security seal to be broken, or for using other approved means of providing security (e.g., audit trail available at the time of inspection as defined in Table S.2.5. Categories of Device and Methods of Sealing) before any change that affects the metrological integrity of the device can be made to any mechanism.

(See discussion of this proposed change in Agenda Item 6)

S.2.5.3. *An event logger is required in the device; it must include an event counter (000 to 999), the parameter ID, the date and time of the change, and the new value of the parameter (for calibration changes consisting of multiple constants, the calibration version number may be used rather than the calibration constants.)*

A printed copy of the information must be available through the device or through another on-site device. The event logger shall have a capacity to retain records equal to 25 times the number of sealable parameters in the device, but not more than 1000 records are required. (Note: Does not require 1000 changes to be stored for each parameter.)

[Nonretroactive as of January 1, 20XX]

(Amended 20XX)

Background / Discussion:

Two common types of removable data storage devices are the USB flash drive and the Secure Digital (SD) memory card. A USB flash drive is a data storage device that includes flash memory with an integrated USB interface. USB flash drives are typically removable and rewritable, and physically much smaller than a floppy disk. A SD card is a non-volatile memory card format originally designed for use in portable devices. The SD standard is maintained by the SD Card Association.

Removable digital storage devices can be used in GMMs as either “data transfer” devices which are not necessary to the operation of the GMM or as “data storage devices” which are necessary to the operation of the GMM.

A USB flash drive is most likely to be used as a “data transfer” device. In a typical “data transfer” application, the USB flash drive is first connected to a computer with access to the web. The computer visits the GMM manufacturer’s web site and downloads the latest grain calibrations that are then stored in the USB flash drive. The USB flash drive is removed from the computer and plugged into a USB port on the GMM. The GMM is put into “remote configuration” mode to copy the new grain calibration data into the GMM’s internal memory. When the GMM has been returned to normal operating (measuring) mode the USB flash drive can be removed from the GMM.

Although an SD memory card could also be used as a “data transfer device” it is more likely to be used as a “data storage device”. In a typical “data storage device” application, the SD memory card stores the grain calibrations used on the GMM. The SD memory card must be plugged into an SD memory card connector on a GMM circuit card for the GMM to operate in measuring mode. To install new grain calibrations the GMM must be turned “off” or put into a mode in which the SD memory card can be safely removed. The SD memory card can either be replaced with an SD memory card that has been programmed with the new grain calibrations or the original SD memory card can be re-programmed with the new grain calibrations in much the same way as that described in the preceding paragraph to copy new grain calibrations into a USB flash drive. In either case, the SD memory card containing the new calibrations must be installed in the GMM for the GMM to operate in measuring mode. In that regard, the SD memory card can be considered a “permanent part” of the GMM in that the GMM cannot operate without it.

Note: In the above example “SD memory card” could be any removable flash memory card such as the Secure Digital Standard-Capacity, the Secure Digital High-Capacity, the Secure Digital Extended-Capacity, and the Secure Digital Input/Output, which combines input/output functions with data storage. These come in three form factors: the original size, the “mini” size, and the “micro” size. “Memory Stick” is a removable flash memory card format, launched by Sony in 1998, and is also used in general to describe the whole family of Memory Sticks. In addition to the original Memory Stick, this family includes the Memory Stick PRO, the Memory Stick Duo, the Memory Stick PRO Duo, the Memory Stick Micro, and the Memory Stick PRO-HG.

See the NCWM S&T Committee 2013-2016 Final Reports and the Grain Analyzer Sector 2013-2016 summaries for additional background information and to review the different proposals considered by the NCWM S&T committee and Grain Analyzer Sectors.

The Grain Analyzer Sector members are asked to review the proposed changes, provide comments and determine if the proposed language is ready to be forwarded to the S&T committee for consideration during the 2018 NIST HB 44 review cycle.

6. Adding a Nonretroactive Requirement to NIST HB 44 Grain Moisture Meter Code 5.56(a) that Grain Moisture Meters meet Category 3 Sealing Requirements

Source:

Grain Analyzer Sector

Purpose:

At the 2016 Grain Analyzer Sector Meeting during its discussion of Agenda Item 5 “Modify the Definition of Remote Configuration Capability that is defined in Appendix D of NIST Handbook 44 to Recognize the Expanded Scope of “Remote Configuration Capability” (S&T Developing item 3600-5)” it was noted that the current technology for sealing grain moisture meters are with event loggers (category 3 sealing requirements). Due to the complexity of these devices, a Category 3 sealing provides a record of what calibration and configuration parameters were changed. As such, the sector discussed including a non-retroactive requirements for category 3 sealing for all grain moisture meters. Currently NIST HB 44 NIR code for devices that measure protein, oil and starch requires that the device be sealed with an event logger. These meters also measure moisture and currently meet category 3 requirements.

Item Under Consideration:

The sector’s technical advisor included the following proposal in the 2016 Grain Analyzer Sector summary for review:

S.2.5. Provision for Sealing.

S.2.5.3. *An event logger is required in the device; it must include an event counter (000 to 999), the parameter ID, the date and time of the change, and the new value of the parameter (for calibration changes consisting of multiple constants, the calibration version number may be used rather than the calibration constants.)*

A printed copy of the information must be available through the device or through another on-site device. The event logger shall have a capacity to retain records equal to 25 times the number of sealable parameters in the device, but not more than 1000 records are required. (Note: Does not require 1000 changes to be stored for each parameter.)

[Nonretroactive as of January 1, 20XX]

(Amended 20XX)

Doug Musik, Kansas Weights and Measures, submitted the following alternate proposal:

Table S.2.5.	
Categories of Device	Methods of Sealing
Category 1¹: <i>No remote configuration capability.</i>	<i>Seal by physical seal or two event counters: one for calibration parameters (000 to 999) and one for configuration parameters (000 to 999). If equipped with event counters, the device must be capable of displaying, or printing through the device or through another on-site device, the contents of the counters.</i>
Category 2¹: <i>Remote configuration capability, but access is controlled by physical hardware.</i> <i>A device shall clearly indicate that it is in the remote configuration mode and shall not be capable of operating in the measure mode while enabled for</i>	<i>The hardware enabling access for remote communication must be at the device and sealed using a physical seal or two event counters: one for calibration parameters (000 to 999) and one for configuration parameters (000 to 999). If equipped with event counters, the device must be capable of displaying, or printing through the device or through another on-site device, the contents of the counters.</i>

<p>Category 3²: Remote and/or no remote configuration capability access. Access may be unlimited or controlled through a software switch (e.g., password).</p> <p>When accessed for the purpose of modifying sealable parameters, the device shall clearly indicate that it is in the configuration mode and shall not be capable of operating in the measuring mode.</p>	<p>An event logger is required in the device; it must include an event counter (000 to 999), the parameter ID, the date and time of the change, and the new value of the parameter (for calibration changes consisting of multiple constants, the calibration version number may be used rather than the calibration constants). A printed copy of the information must be available through the device or through another on-site device. The event logger shall have a capacity to retain records equal to 25 times the number of sealable parameters in the device, but not more than 1000 records are required. (Note: Does not require 1000 changes to be stored for each parameter.)</p>
<p>Category 3a: No remote capability, but operator is able to make changes that affect the metrological integrity of the device (e.g., slope, bias, etc.) in normal operation.</p> <p>*When accessed for the purpose of modifying sealable parameters, the device shall clearly indicate that it is in the configuration mode and shall not be capable of</p>	<p>Same as Category 3</p>
<p>Category 3b: No remote capability, but access to metrological parameters is controlled through a software switch (e.g., password).</p> <p>*When accessed for the purpose of modifying sealable parameters, the device shall clearly indicate that it is in</p>	<p>Same as Category 3</p>
<p>¹ Not allowed for devices manufactured on or after January 1, 2019</p>	
<p>² Required for all devices manufactured on or after January 1, 2019</p>	

[Nonretroactive as of January 1, 1999]
 [*Nonretroactive as of January 1, 2014]
 (Amended 1998 and 2013 and XXXX)

Background / Discussion:

During discussion of Agenda Item 5 above during the 2016 GA Sector meeting, it was suggested that the Grain Moisture Meter Code requirements for sealing be changed such that all grain moisture meters are required to meet category 3 sealing requirements as of a specific date; e.g. all grain moisture meters must have an event logger. With the increase in ease of switching out removable SD cards and making changes to metrological components it may be time to require a form of sealing that provides information on what was changed and the date of the change to the device. Category 3 sealing is currently required in NIST HB 44, Section 5.57, NIR Code. Manufacturers that were present at the meeting did not object to the proposal, but it was noted that all manufacturers were not represented at the meeting. During the 2016 GA sector meeting, Jim Truex also noted that we may need to consider State laws that require that a commercial device have a lead and wire seal. It was also mentioned that the proposed NIST, LMDP language for the general code would be redundant for the grain code if language is added to the grain moisture meter code that grain moisture meters be equipped with an event logger.

The current status for sealing methods of grain moisture meters are as follows:

Inactive Certificates of Conformance (CC):

- 9 inactive certificates; an inactive status for grain analyzers means that a CC was previously active for a device, but now the device is no longer being manufactured or remanufactured. Existing devices may be used, sold, or repaired and resold under inactive certificates. As such, these devices are likely still in use.
 - 3 inactive devices are *not* sealed using an event logger.

Active CC

- 9 active certificates
 - 1 active device is *not* sealed using an event logger.

The Grain Analyzer Sector members are asked to review the proposed changes, provide comments and discussion on the proposed language for changes to the sealing requirements in NIST HB 44, Section 5.56(a).

7. Report on International Organization of Legal Metrology (OIML) TC 17/SC 1 R 59 *Moisture Meters for Cereal Grains and Oilseeds*

Background / Discussion:

This item is included on the Sector's agenda to provide a summary of the activities of OIML TC17/SC1 to the grain analyzer sector and to those Sector members that participate on the United States National Working Group (USNWG) on grain moisture meters.

OIML TC17/SC1 was tasked to revise OIML R 59 *Moisture Meters for Cereal Grains and Oilseeds* to reflect new technologies and actual grain analysis. The Co-Secretariats (China and the United States) worked closely with an International Project Group to revise OIML Recommendation R 59 *Moisture Meters for Cereal Grains and Oilseeds*.

As reported at the 2016 GA Sector meeting, OIML R59 would be voted on at the 51st CIML Meeting. OIML R 59 *Moisture Meters for Cereal Grains and Oilseeds* was approved at the 51st CIML meeting, held October 17-21, 2016.

Grain moisture meter manufacturers were notified by e-mail on May 9, 2017 that OIML R59 2016 was published and available on the OIML website at https://www.oiml.org/en/files/pdf_r/r059-p-e16.pdf. In this e-mail NIST OWM requested any feedback or statement on how this standard impacts your company that can be used in NIST highlights to demonstrate the impact of our work in OIML. If you have not provided a statement or feedback please send this information to diane.lee@nist.gov.

8. Report on OIML TC 17/SC 8 *Protein Measuring Instruments for Cereal Grains and Oil Seeds*

Background / Discussion:

This item is included on the sector's agenda to provide a summary of the activities of OIML TC 17/SC 8 to the grain analyzer sector and to those Sector members that participate on the United States National Working Group (USNWG) on grain protein measuring instruments.

OIML TC17/SC8 was formed to study the issues and to develop a Recommendation on *Protein Measuring Instruments for Cereal Grain and Oil Seeds (OIML R 146)*. Australia is the Secretariat for this subcommittee.

As reported at the 2016 GA Sector meeting, OIML R 146 would be voted on at the 51st CIML Meeting. OIML R 146 *Protein Measuring Instruments for Cereal Grain and Oil Seeds* was approved at the CIML meeting, held October 17-21, 2016.

Grain moisture meter manufacturers were notified by e-mail on May 9, 2017 that OIML R146 *Protein Measuring Instruments for Cereal Grain and Oil Seeds* was published and available on the OIML website at https://www.oiml.org/en/files/pdf_r/r146-p-e16.pdf. In this e-mail NIST OWM requested any feedback or statement

on how this standard impacts your company that can be used in NIST highlights to demonstrate the impact of our work in OIML. If you have not provided a statement or feedback please send this information to diane.lee@nist.gov.

9. Air-Oven Grain Moisture Proficiency/Collaborative Study/Interlaboratory Comparison Testing

Source:

Grain Analyzer Sector

Purpose:

Develop an air-oven proficiency/collaborative study/interlaboratory comparison testing program to ensure state laboratory and manufacturer's air-oven measurements are traceable to the official USDA, GIPSA air-oven measurements.

Item Under Consideration:

Establish a timeline for consistent and periodic grain moisture proficiency testing.

Background/Discussion:

Under the NTEP program for grain moisture meters, calibrations are based on USDA/GIPSA air ovens while field inspection is based on State air ovens. For the program to be effective, procedures must be in place to assure that State oven results (and manufacturers' oven results) agree with the USDA/GIPSA air oven, which is, considered the standard. NIST-OWM's laboratory measurement traceability program requires that laboratories participate in interlaboratory and other collaborative experiments. This requirement has been met by one of two methods: 1) individual laboratories independently send samples to GIPSA for air oven analysis, and subsequently compare their results to those obtained by GIPSA; or 2) a structured collaborative study where every lab, including GIPSA, measure the same sample. A structured collaborative study has at least two advantages over independent submission of samples to GIPSA by individual laboratories: 1) in addition to a check against the "standard", it provides information on how individual labs compare with each other; 2) it allows GIPSA to plan for a known work load.

A collaborative air oven study has been conducted with States and meter manufacturers periodically over a number of years and results discussed during the GA Sector meetings. These studies were conducted in 1995, 2001 and 2015.

At the 2009 NTETC Grain Analyzer Sector Meeting Dr. Hurburgh, Iowa State University, urged the representatives from the American Oil Chemists Society (AOCS) to prepare a proposal so that the collaborative (air-oven) study could be conducted on an on-going basis rather than on an ad hoc basis. He cautioned that the proposal would have to include corn and wheat as well as soybeans and at the 2011 NTETC Grain Analyzer Sector Meeting, Ms. Johnson, AOCS, proposed an air-oven/GMM proficiency testing series designed specifically to address the needs of GMM manufacturers and states maintaining a grain moisture laboratory. The intent was for the AOCS to administer, oversee distribution of samples, compile results, perform statistical analysis of results, and distribute a report to participants. AOCS does not collect the samples. This is subcontracted to suitable providers. AOCS does not have laboratories. Since GIPSA/ FGIS is a certified laboratory already participating in the AOCS Soybean Quality Traits program, GIPSA air-oven results could be reported for comparison

At the sector's August 2012 meeting the sector learned that Ms. Christine Atkinson will be taking over the Proficiency Testing program for States and interested manufacturers formerly headed by Ms. Amy Johnson. Ms. Atkinson verified that participant's cost will remain \$100 per year. The sector reiterated that the program should focus solely on the standard FGIS air-oven method. Instrument results will not be reported. Participants' air-oven results will be compared against GIPSA's standard FGIS air-oven results. In response to Ms. Atkinson's question about scheduling, the sector was in general agreement that samples should ship after harvest, preferably between mid-January and mid-February with participants' results due 30 days after the shipping date.

The sector agreed upon the following Program Details:

Samples – Soybeans 2, Corn 2, Hard Red Winter Wheat 2

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- Cost to Participants - \$100.00/year
- Schedule:
 - Samples (6) ship between January 15 and February 15.
 - Samples must be tested within 5 business days of receipt with results due 30 days after the shipping date.
- Reports to be posted on www.SoybeanQualityTraits.org by 1 May.
- Only the GIPSA oven results will be identified. Individual manufacturer's and State participant's oven results will be assigned an identifier known only to the manufacturer or State participant. Instrument results will not be reported.
- Detailed Participant Instructions will be provided to each participant.

At the August 2013 Grain Analyzer Sector meeting no report was provided on AOAC's efforts to conduct proficiency testing for grain moisture. As such, Karl Cunningham, IL and Kevin Hanson, MO agreed to work together to conduct a grain moisture proficiency test. Karl Cunningham, IL, agreed to provide the samples for proficiency testing and Kevin Hanson, MO, agreed to analyze the data in accordance with the procedures used to conduct proficiency testing in the State laboratory program. Kevin also agreed to collect data on test weight per bushel which may be useful in field test procedures for evaluating test weight per bushel on instruments. Following the August 2013 sector meeting arrangements were made for shipping grain samples to State participants.

At the August 2014 Grain Analyzer Sector meeting Mr. Karl Cunningham provide an update on the status of proficiency testing. Mr. Cunningham informed the Grain Analyzer Sector that he collected some wheat grain samples that can be used for grain moisture proficiency testing and that corn and soybeans will be collected during the 2014 harvest. Mr. Cunningham noted that after January 2015 wheat, corn and soybeans grain samples may be ready for distribution to the participating States. Mr. Cunningham agreed to analyze the data in cooperation with NIST and requested a list of contact information for participating States and other interested parties. Proficiency testing was conducted in 2015 and reported in the 2015 Grain Analyzer Sector Report (Note: In 2015, a Grain Analyzer Sector meeting was not held but a report of activities was generated)

Recommendation:

Although the Sector has periodically conducted proficiency testing over the years, a schedule of ongoing proficiency testing is needed to ensure that these test are performed on a consistent basis. With changes in responsibilities in AOAC and loss connections, establishing an ongoing collaborative study with AOAC may be difficult to manage. As such the Grain Analyzer Sector is asked to consider the following timeline previously discussed for sending out samples and using the guidelines for proficiency testing which includes frequency of testing included in NISTIR 7082 "Proficiency Test Policy and Plan (For State Weights and Measures Laboratories), and tools and forms for analyzing the results which are located on the NIST OWM Website at:

<https://www.nist.gov/sites/default/files/documents/2017/05/09/nistir-7082.pdf>

It is suggested that the proficiency testing be managed and oversight provided by State Weights and Measures, Grain Analyzer Sector members on a rotating basis. Per NISTIR 7082, the frequency of proficiency testing for grain moisture air oven measurements is 4 years or more often. As such the following schedule is proposed for discussion. Please note that in addition to testing corn, soybeans and wheat the sector is asked to consider any benefits to including one specialty grain such as corn modified for high ethanol production to the proficiency testing. The schedule will be reviewed at the Sector meeting preceding the scheduled proficiency test date to confirm responsible parties and any specialty grains for inclusion in the proficiency test year. The specialty grain will change based on specific market concerns during the proficiency test year.

Air Oven Grain Moisture Proficiency Testing Schedule (Previous PTs 1995, 2001 and 2015)					
PT Test Date 4 yr Cycle	Sample Collection Date	Samples for Testing 2 of each (corn, wheat, soybeans) + 1 specialty grain	Sample Ship Date	Responsible for Sample Distribution w/ Instructions	Responsible for Data Collection and Analysis
Spr 2019	Spr 2018	specialty grain: <u>Corn modified for high ethanol production</u>	Jan/Feb 2019	IL	IL
Spr 2023	Spr 2022	Specialty grain ____?	Jan/Feb 2023	____?	____?
Spr 2027	Spr 2026	Specialty grain ____?	Jan/Feb 2027	____?	____?

10. The Feasibility of a Phase II program for Near Infrared Grain Analyzers

Source:

Dr. Hurburgh, Iowa State University

Background/Discussion:

The GIPSA Grain Inspection Advisory Committee recommends that GIPSA initiate research to determine the feasibility of extending the theory of “equivalency” to multiple-constituent instruments in order to utilize standardized technology while maintaining accuracy and consistency in measurement of wheat protein.

Ms. Eigenmann provided an update on the Grain Inspection Advisory Committee’s Resolutions. The Sector discuss the feasibility of an ongoing calibration program also referred to as a Phase II program for Near Infrared Grain Analyzers (NIR) instruments that measure wheat program. The Phase II program for grain moisture is a program that monitors the moisture calibrations on grain moisture meters annually. As changes to the calibrations occur due to grains, climate, etc., data collected in this program allows for changes to moisture calibrations annually and ensure equivalency among the different moisture meter models. The Advisory committee is recommending that this program be extended to include NIR instruments that measure wheat protein. It was noted that there could be multiple NIR instruments for wheat protein introduced into the market and that it may be advisable to have the Phase II program extended to NIR instruments that measure wheat protein. It was also mentioned that currently there are few States that are checking wheat protein on multi-constituent instruments.

GIPSA currently has an annual review program for the official protein system but would have to consider the cost associated with extending the program for other NIR wheat protein analyzers. It was noted during the discussion that GIPSA currently has hourly rate fees set that could be applied to a phase II program for wheat program.

Unlike moisture where there may be changes to the calibrations annually, there will not be year to year changes for wheat protein. As such, consideration may be given to conducting the program less than annually, and considering reviewing wheat protein calibrations every 3, 4, or 5 years, as appropriate. In addition it was noted that there also has to be a mechanism to get manufacturers calibration data for calibration review.

The sector will continue to discuss the feasibility of a phase II program for wheat protein giving consideration to the following issues:

- How the program will be funded,
- How often the calibrations for wheat protein will be updated,
- How many devices are currently being used in commercial transactions, and
- If being used commercially in a State, what is needed by States to begin testing these devices?

At the August 2014 Grain Analyzer Sector meeting USDA, GIPSA representatives provided an update on the activities concerning a phase II program for wheat protein. The Sector was informed that USDA, GIPSA is discussing funding options for this program. It was noted that the frequency of calibration for wheat protein is being considered and that

this will impact the cost of the program. The Sector was also informed that Dr. David Funk is writing a discussion paper that will address many of the issues concerning a Phase II program for wheat protein.

2015 Grain Analyzer Sector Report Update:

USDA, GIPSA representatives mentioned that they are not aware of a discussion paper from Dave Funk concerning the feasibility of a Phase II program for Near Infrared Grain Analyzers. The sector should continue to provide feedback on the four bullet items listed above and USDA, GIPSA should provide any updates on any internal discussions.

2016 Grain Analyzer Sector Meeting Update

Mr Jordan, GIPSA, the NTEP Participating Laboratory for grain analyzers provided information on some work involving applying data transforms to spectra of multiple instrument models and provided an update of these activities along with others involved in considering Phase II testing for Near Infrared Grain Analyzers.

During the 2016 Grain Analyzer Sector meeting, the sector agreed that a program is needed based on observations and some feedback from sector members that review calibration data for these instruments. As such, the sector “brain stormed” ideas on what would be needed to develop a phase II program to periodically verify the calibrations on Near Infrared devices. The sector members generated the following information based on its discussion:

Near Infrared Phase II Program Needs:

- Set of robust samples that can be used every year,
- A reference laboratory to perform the testing,
- 100 samples for all meters or less per grain type on each meter,
- The program should verify calibrations for basic grains where there is a commercial impact to included protein in wheat, soybeans, barley, and corn and oil in corn and soybeans (it was noted during discussion that there is a large economic impact in the area of wheat protein and that protein and oil in corn and soybeans are used in many non-trade applications).
- The program would currently include a total number of three instruments (There are three instruments that measure protein and oil in the NTEP program)
- Testing should include a slope bias test for each 2 point intervals and include a confidence interval.
- The current NCWM, Inc policies for participating in the grain moisture phase II testing can be used for the near infrared phase II program.
- An estimate of the cost of the program is needed. There was also a question as to whether or not the cost of the program would be distributed among the participating manufacturers, similar to the Phase II program for grain moisture.

In addition to the discussion of program needs for Phase II testing for near infrared devices, it was noted that although States test near infrared devices for grain moisture measurements, not many States are evaluating these devices for protein or other grain constituents (oil or starch). The GA Sector also discussed the needs of State weights and measures jurisdictions in testing near infrared devices for protein, starch and oil. It was noted that State resources: staff and money are needed for testing and that currently, per the States that attended the Sector meeting, commercial transactions involving protein measurements are lower than for grain moisture measurements.

Recommendation:

Sector members are asked to review the background information and list of program needs for this item in preparation for discussion on how to meet the needs for a Phase II testing program for Near Infrared Grain Analyzers.

11. State Weights and Measures Issues with Inspection of Grain Moisture Meters for Corn /Tolerances for UGMA meters

Source:

G. Diane Lee, NIST, OWM, Legal Metrology Device Group

Background / Discussion:

Diane Lee, NIST OWM received calls requesting a copy of the annual request for grain samples and list of grains that GIPSA request from States to include in the ongoing calibration program. These request came from various States and other interested parties. One State reported seeing a difference between a UGMA meter and another meter on corn samples and wanted to ensure that grain samples in their State were represented in the ongoing calibration program.

2016 Grain Moisture Meter Sector Meeting

During the discussion of this item at the 2016 Grain Analyzer Sector meeting it was mentioned that this issue arised when two states would not accept the new corn calibrations for grain moisture meters when they observed a difference in results for corn on different meter technologies. During the discussion it was noted that the States that reported problems with the corn calibrations were States that have high ethanol production. It was explained that States with high ethanol production may have a high production of modified corn (corn modified to increase ethanol production). Since calibrations are based on a national sample set with grains collected from across the U.S., these modified samples may not have been included in the national sample set which could have contributed to the irregularities with the updated corn calibrations. It was suggested during the Sector meeting that modified corn samples be included in the national sample set and to monitor corn calibrations and modified corns for ethanol production. It was also noted that States should use the recommended procedures in NIST HB 44 when testing to ensure that error are not introduced due to incorrect test procedures.

Following the discussion of this agenda item, Jeff McCluer, who had submitted an item to include on the 2016 sector agenda, that was ultimately not included on the agenda based on his request to change GIPSA tolerances, which is not in the scope of the GA Sector, presented information in reference to tolerance for UGMA meters. He explained that if the UGMA meter technology can make better measurements, he recommends that a reduction in the tolerances should be made. Charlie Hurburgh noted that the Sector has not conducted a study of the new technology and that a task force could be developed to take a look at the results of these meters. Charlie Hurburgh agreed to chair the task group to look at results from UGMA meters.

After some discussion with Dave Funk, Grain Quality Analytics, LLC and some research on the tolerances for UGMA meters. At the temperature extremes errors in measurement are increased so the tolerances were set to account for an average error in these meters. As such, the task group should include a review of the measurements at varing temperature ranges.

Recommendation:

The Sector is asked to review this item and discuss specific arrangements for developing a task group to review tolerances and different technologies.

Next Sector Meeting

The next meeting is tentatively planned for Wednesday, August 15 (1:00 p.m. to 5:00 p.m.) and Thursday, August 16, 2017, at the Hyatt Place at the Kansas City, MO Airport. Sector members are asked to hold these days open pending confirmation of availability of facility, determination of agenda items, exact meeting times, and meeting duration. Final meeting details will be announced by early June 2017.

If you would like to submit an agenda item for the 2017 meeting, please contact any of the following persons by June 1, 2015:

Jim Truex, NTEP Administrator at jim.truex@ncwm.net
G. Diane Lee, NIST Technical Advisor, at diane.lee@nist.gov